

**Search Notes**

Application/Control No.

10/664,740

Examiner

Maikhanh Nguyen

Applicant(s)/Patent under  
Reexamination

YALOVSKY ET AL.

Art Unit

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	513 530	2/14/2006	MK
715	526	2/14/2006	MK
709	219,229	2/14/2006	MK
Updated	above	10/6/2006	MK
Updated	above	6/27/2007	MK
Updated	above	12/19/2007	MK
715	769 770	12/19/2007	MK
709	203	12/19/2007	MK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	513	12/19/2007	MK
	530 770	12/19/2007	MK
709	203	12/19/2007	MK
USPAT - USPGPub		12/19/2007	MK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search	2/14/2006	
West Search (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout	2/14/2006	MK
West Search (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout	10/6/2006	MK
West Search (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout	6/27/2007	MK
Consulted with William Bashore (Primary Examiner)	12/17/2007	MK
West Updated (USPAT, USPGPub, EPO, JPO, DERWENT) - See Search History Printout	12/19/2007	MK
Interference Search - See Search History Printout	12/19/2007	MK